

Press Release

ILSIT Japan Elects DCG Systems and Hamamatsu Photonics to Membership on Its Organization Committee

OSAKA, JAPAN, Nov 01, 2010 (MARKETWIRE via COMTEX) -- The Institute of LSI Testing (ILSIT) announced today that DCG Systems and Hamamatsu Photonics have been elected to membership on the ILSIT Organization Committee. Members include technology leaders from Toyota Motors, Renesas Electronics, Oita Univ., Univ. of Tokyo, Osaka Univ., Hitachi High-Tech., JOEL Ltd, and Toshiba. DCG and Hamamatsu have been added as the third and fourth vendor on this Committee.

ILSIT was founded in 2006 by Professor Koji Nakamae (Osaka University) to sponsor the LSI Testing Symposium (LSITS) and is currently chaired by him. Since 1981, LSITS is recognized as the foremost technical conference in Japan dedicated to the diagnostics and testing of LSI circuits. The conference is held in cooperation with the Institute of Electronics, Information and Communication Engineering, the Japan Society of Applied Physics, Reliability Engineering Association of Japan and Union of Japanese Scientists and Engineers. LSITS brings together engineers and scientists from industries and universities to discuss recent progress and future trends in semiconductor analysis.

The Organization Committee of ILSIT includes a broad range of expertise, including Professor Kiyoshi Nikawa (Osaka University), the inventor of "Optical Beam Induced Resistance Change" (OBIRCH), Dr. Toshiyuki Majima (Renesas Electronics), the inventor of "Electron Beam Adsorbed Current" (EBAC) and Dr. Toru Koyama (Renesas Electronics), the developer of "Forming the Si substrate into a Solid Immersion Lens" (FOSSIL) and 7 other technology leaders from industry and academia. DCG's role on the committee is to promote a greater international presence at the LSITS.

About the Institute of LSI Testing The Institute of LSI Testing, associated with Osaka University's Department of Information Systems Engineering, sponsors the LSI Testing Symposium to contribute to progress in LSI testing technology. The ILSIT is dedicated to improving testing of LSI circuits, covering the complete cycle from test design, manufacturing process, test, fault diagnosis, failure analysis and back to process and design improvement. The LSITS will continue to be an important forum for semiconductor companies, major users, universities and vendors to discuss technology. Now, more than ever, ILSIT is playing an increasingly important role in organizing the industry's meeting place. For more information visit: <http://www-LSITS.ist.osaka-u.ac.jp>.

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